REMARKS

This Amendment and Response to the final Office Action mailed February 4, 2005 is being filed concurrently with a Request for Continuation Examination.

In response to the Office action mailed November 19, 2004, Applicant respectfully requests reconsideration. To further the prosecution of the application, claims 21 and 25 are amended. Claims 9-13 and 19 were previously withdrawn or canceled. Accordingly, claims 1-8, 14-18 and 20-25 remain pending, of which claims 1, 14, 20 and 21 are in independent form. The application as presented is believed to be in allowable condition.

Applicant submits a Terminal Disclaimer in compliance with 37 C.F.R. §1.321(c) to overcome the rejection of claims 14-18 on the basis of the judicially created doctrine of obviousness-type double patenting. Specifically, Applicant submits a Terminal Disclaimer and fee to disclaim the terminal part of the statutory term beyond U.S. Patent No. 6,891,967, which is owned by the assignee of the present application, Speedline Technologies, Inc. Accordingly, reconsideration of the rejection of claims 14-18 is respectfully requested.

With respect to the rejection of claim 25 under 35 U.S.C. §112, second paragraph, Applicant has cured this error by amending claim 25 to specify a method, which properly depends on another method claim, i.e., claim 24. Reconsideration of the rejection of claim 25 is respectfully requested.

In the Office action, claims 21-25 were rejected under 35 U.S.C. §103(a) as being obvious and unpatentable over Doyle et al. (U.S. Patent No. 5,873,939) in view of Takagi et al. (U.S. Patent No. 5,801,965) and in further view of Chang et al. (U.S. Publication No. 2002/0019729 A1).

As amended, claim 21 is directed to a method of dispensing material at predetermined locations through a stencil and onto an electronic substrate. The method comprises:

(a) delivering a substrate to a stencil printer;

(b) positioning the substrate in a print position;

(c) positioning a stencil onto the substrate;

(d) dispensing the material through the stencil and onto the substrate;

(e) performing texture-based recognition of a predetermined location of the material on a bottom side of the stencil;

(f) determining whether there is at least one feature in the predetermined location on the bottom side of the stencil;

(g) comparing the at least one feature on the bottom side of the stencil with a position of the substance on the substrate to determine whether the at least one feature is a defect; and

(h) actuating a stencil wipe procedure to clean the bottom side of the stencil when the at least one feature is determined to be a defect.

In the Office Action, the Examiner asserts that Doyle et al. disclose dispensing material through the stencil on to the substrate. The Examiner further asserts that Takagi et al. disclose a texture-based recognition for detecting defects. Lastly, the Examiner asserts that Chang et al. teach actuating a stencil wipe procedure to clean the stencil when a defect exists in the region of interest, and that it would have been obvious to one of ordinary skill in the art at the time of the invention to combine the references.

Applicant respectfully disagrees. Applicant has amended claim 21 by specifying that the method is performed within a stencil printer and that a stencil print operation is being performed on the substrate. Chang et al. teach the use of a mask inspection system and method to repair or replace a photolithography mask within a system adapted to manufacture an integrated circuit. Firstly, a person skilled in the art of printed circuit board fabrication would not turn to the semiconductor industry. Secondly, Takagi et al., contrary to the Examiner's assertion, does not teach a texture-based recognition procedure as set forth in claim 21 and in Applicant's specification. Specifically, Takagi et al. merely reference the obtainment of "texture information," but does not teach performing texture-based recognition of a predetermined location of the material on a bottom side of the stencil.

Thirdly, and perhaps most importantly, notwithstanding the properness of combination of Chang et al. and Takagi et al. with Doyle et al., there is no teaching, showing or suggestion in any of these references of a method including performing a texture-based recognition of the bottom side of the stencil, determining whether there is one feature on the stencil, comparing the feature with the substrate to determine whether the feature is a defect, and actuating a stencil

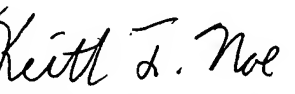
wipe procedure to clean the bottom side of the stencil when the feature is a defect. The performance of these claimed method steps is clearly lacking from the references. Thus, claim 21 is submitted as non-obvious and patentable over the references relied on by the Examiner.

Claims 22-25, which depend directly or indirectly from claim 21, are patentable for at least the same reasons as claim 21.

CONCLUSION

Based on the foregoing, the application is believed to be in allowable condition and a notice to that effect is respectfully requested. If the Examiner has any questions regarding the application, he is invited to contact the Applicants' Attorney at the number provided below.

Respectfully submitted,



Keith F. Noe, Esq. (Reg. No. 34,686)
LOWRIE, LANDO & ANASTASI, LLP
Riverfront Office Park
One Main Street
Cambridge, MA 02142
Tel.: (617) 395-7039
Fax: (617) 395-7070
Attorney for Applicant

Dated: February 6, 2006
Attorney Docket No.: M2010-7128

779474.1